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Certificate of Participation

This is to certify that

Yukiho Shibasaki, Koji Asami, Riko Aoki, Akemi Hatta, Anna Kuwana and Haruo Kobayashi

has presented a paper titled

Analysis and Design of Multi-Tone Signal Generation Algorithms for Reducing Crest Factor

at the 29th IEEE Asian Test Symposium hosted virtually from Malaysia on November 22-25, 2020.

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